

FDS4410

Single N-Channel Logic Level PWM Optimized PowerTrenchTM MOSFET

General Description Features

This N-Channel Logic Level MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

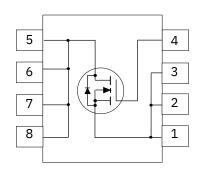
The MOSFET features faster switching and lower gate charge than other MOSFETs with comparable R specifications. $$_{\rm DS(ON)}$$

The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

- * 10 (0 N) = 0.0135 @ VGS = 10 V RDS(ON) = 0.0200 @ VGS = 4.5 V.
- Optimized for use in switching DC/DC converters with PWM controllers.
- Very fast switching .
- Low gate charge (typical 22 nC).







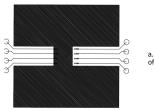
Absolute Maximum Ratings $T_A = Q_{5C \text{ unless other wise noted}}$

Symbol	Parameter	FDS4410	Units
V _{DSS}	Drain-Source Voltage	30	V
V _{GSS}	Gate-Source Voltage	±20	V
Þ	Drain Current - Continuous (Note 1a)	10	А
	- Pulsed	50	
P _D	Power Dissipation for Single Operation Note 1a)	2.5	W
	(Note 1b)	1.2	
	(Note 1c)	1	
Т _{Ј.Тѕтс}	Operating and Storage Temperature Range	-55 to 150	°C
	CHARACTERISTICS		
$R_{\theta^{JA}}$	Thermal Resistance, Junction-to- (Note	5	°C/
R JC	Ambient Thermal Resistance ¹ a)	0	W
θ	Junction-to-Case (Note 1)	2	°C/

Electrical Characteristics (150 unless otherwise Symbol Parameter		Conditions	Min	Тур	Max	Units
OFF CHARA	CTERISTICS	1		'		
BVDSS	Drain-Source Breakdown Voltage	VGS = 0 V, I D = 250 μA	30			V
$\Delta BV_{DSS}/\Delta T$	Breakdown Voltage Temp. Coefficient	I50 μA, Referenced to 25 o D = 2C		21		mV /oC
I _{DSS}	Zero Gate Voltage Drain Current	V V			1	μA
		DS = 24 V, VGS = 0 V			10	μΑ
\mathbf{I}_{GSSF}	Gate - Body Leakage,	V GS = 20 V, VDS = 0 V			100	nA
I GSSR	Forward Gate - Body	VGS = -20 V, VDS = 0 V			-10	nA
ON CHARAC	CTERNSTER STERVENCE	, , , , , , , , , , , , , , , , , , , ,			0	-
V _{GS(th)}	Gate Threshold Voltage	V DS = VGS, ID = 250 μA	1	2	3	V
$\Delta V_{GS(th)}/\Delta T_{T}$	Gate Threshold Voltage Temp. Coefficient	I50 μA, Ro		-4.5		mV /oC
RDS(ON)	Static Drain-Source On-Resistance	D = 2eferenced to 25 C		0.011	0.013	35 Ω
		V		0.018	0.023	-
		GS = 10 V, I D = 10 A		0.017	0.02	1
$I_{D(ON)}$	On-State Drain Current	VGS = 10 V, VDS = 5 V	50		Α	
g s	Forward Transconductance	VDS = 10 V, I D= 10 A		27	S	
	HARACTERISTICS	,				
C _{iss}	Input Capacitance	VDS = 15 V, VGS = 0 - V, f = 1.0 MHz		134		pF
Cos	Output Capacitance	V, f = 1.0 MHz		0		pF
Cs	Reverse Transfer Capacitance			340		pF
SWITCHING	G CHARACTERISTICS(Note 2)			125		•
t D(on)	Turn - On Delay	VS= 15 V, I D= 1 A		1	2	ns
t	Time Turn - On	ν 6 Ω		2	2	ns
r	Rise Time	GS = 10 V , RGEN =		1	2	ns
t D(off)	Turn - Off Delay			3	4	ns
t	Time	VS = 15 V, I D = 10 A,		3	6	nC
f O	Turn - Off Fall Time	V		8	0	nC
g	Total Gate Charge	GS = 10 V		1	1	nC
DRAIN-SOURGE DIODE CHARACTERISTICS AND MAXIMUM RATINGS					8	•
p	পিঞ্জাপ্রথা Continuous Drain-Source Diode F	orward Current		2	3.	Α
W 6€2)	ਰਿਸ਼ਜ਼-ਤਿਰਪਾਟੀ ਚਿਫਿਰ Forward VoltageVGS =	0 V, IS = 2.1 A		0 <u>2</u> 73	1	V
lotes:			•	5	1.	
P						

^{1.} R

6JA is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting durface of the drain pins. R0^{sc} is guaranteed by design while R
6CA is determined by the user's board design.



a. 500C/W on a 1 in2 pad of 2oz copper.





Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%.

Typical Electrical Characteristics

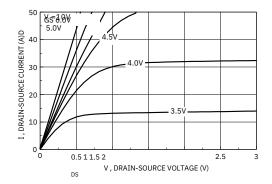


Figure 1. On-Region Characteristics.

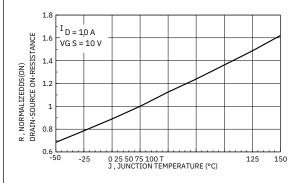


Figure 3. On-Resistance Variation with Temperature.

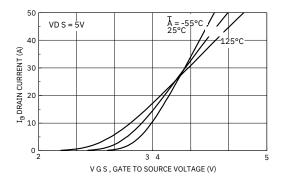


Figure 5. Transfer Characteristics.

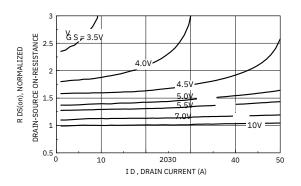


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

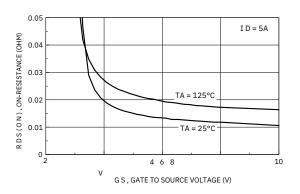


Figure 4 . On-Resistance Variation with Gate-to-Source Voltage.

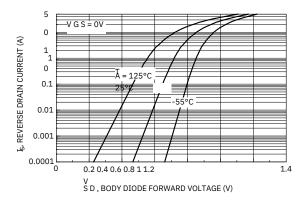


Figure 6 . Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Electrical And Thermal Characteristics

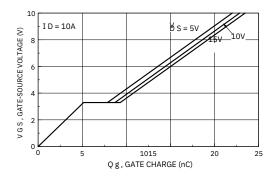


Figure 7. Gate Charge Characteristics.

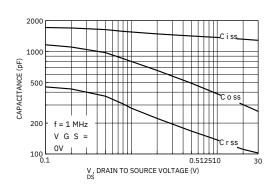


Figure 8. Capacitance Characteristics.

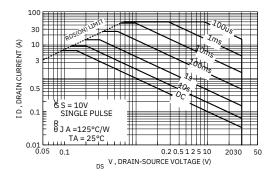


Figure 9. Maximum Safe Operating Area.

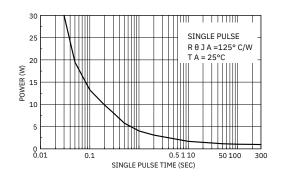


Figure 10. Single Pulse Maximum Power Dissipation.

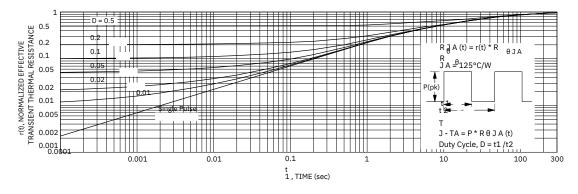


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

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